Information for Authors

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CES Transactions on Electrical Machines and Systems (CES TEMS) is an international quarterly journal, which is published by the China Electrotechnical Society (CES) and the Institute of Electrical Engineering of the Chinese Academy of Sciences, and technically co-sponsored by IEEE Power Electronics Society (IEEE PELS). The CES TEMS will be published in IEEE Xplore and be submitted to EI Compendex.

Scope

CES TEMS aims to establish a high-end academic communication platform to present the latest R & D achievements in the fields of electrical machines and systems in a timely fashion, and to attract the relevant researchers and professionals from all over the world to exchange technical information and experiences. And the Journal will publish original peer-reviewed technical and review articles covering a broad range of topics related to electrical machines and systems, including but not limited to: design, implementation and integration of

- > high performance electric machines
- > motor drives
- > power electronics and its applications
- efficient energy conversion
- > motion control and servo systems
- photovoltaic power generation
- > wind power
- reliability and fault diagnosis
- > magnetic field analysis
- new material applications
- electromagnetic compatibility
- > electrification of transportation

Types of papers

- Original research papers
- ➤ Review articles, which summarize the most up-to-date achievements on a particular topic, and provide foresight concerning future trends
- ➤ Rapid communications which reporting the latest findings or advances which are deemed to be of significant importance.

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